

PCN 18 0212

Qualification Results Summary of ADA4571

QUALIFICATION RESULTS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Early Life Failure Rate (ELFR)	AEC-Q100-008	3x800	Pass
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	4x77	Pass
Low Temperature Operating Life (LTOL)*	JEDEC <i>JESD22-A108</i>	3x77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3x77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3x77	Pass
Unbiased HAST (UHST)*	JEDEC <i>JESD22-A118</i>	3x77	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3x11	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3x77	Pass
Latch-Up	JEDEC <i>JESD78</i>	1x15	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass _4000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 1250V
Electrostatic Discharge <i>Machine Model</i>	JEDEC <i>JESD22-A115</i>	3/voltage	Pass 300V

* These samples were subjected to preconditioning (per J-STD-020 Level 1) prior to the start of the stress test. Level 3 preconditioning consists of the following: 1. Bake – 24 hours at 125°C; 2. Soak – unbiased soak for 168 hours at 85°C, 85%RH; 3. Reflow – three passes through a reflow oven with a peak temperature of 260°C. TC samples were subjected to wire-pull test after 2000 cycles with results within specification limits.